

<b>Notice of References Cited</b>	Application/Control No. 10/628,822	Applicant(s)/Patent Under Reexamination WALKER ET AL.	
	Examiner Siu M. Lee	Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0099882 A1	07-2002	Denda et al.	710/38
*	B	US-6,741,834 B1	05-2004	Godwin, John P.	455/3.01
*	C	US-2003/0054758 A1	03-2003	Kawamata et al.	455/3.04
*	D	US-2004/0198389 A1	10-2004	Alcock et al.	455/456.1
*	E	US-2004/0192189 A1	09-2004	Yuhara et al.	455/003.02
*	F	US-5,548,828	08-1996	Kozaki et al.	455/161.2
*	G	US-5,701,161	12-1997	Williams et al.	348/468
*	H	US-5,797,087	08-1998	Lee, Hyo Chan	455/181.1
*	I	US-6,829,475 B1	12-2004	Lee et al.	455/419
*	J	US-5,950,112	09-1999	Hori et al.	725/148
*	K	US-5,969,634	10-1999	Takashima et al.	340/7.34
*	L	US-5,404,566	04-1995	Wehrmeyer, Buckhard	455/3.06
*	M	US-6,628,930 B1	09-2003	Vogt et al.	455/131

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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